

RELIABILITY MONITOR

DS1000M-100 OCT '99 MONITOR

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1000	E3	9944	DH927108AJC	8	DIP	300	CPS (ChipPac, C
PROCESS Single Poly, Single Metal 1.2 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
24791	INFANT LIFE	125C, 7.0 VOLTS	231	48	HOUR	2
24792	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	75	336	HOUR	0
		125C, 7.0 VOLTS	75	1000	HOUR	0
		TOTAL:	103	DEVICE HRS: 3.01E+07		2
24793	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
		TOTAL:				0
24794	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			77	959	HOUR	0
		TOTAL:				0
24795	AUTOCLAVE	121C STEAM, UNBIASED	37	96	HOUR	0
		TOTAL:				0
JOB NO	FAILURE MODE	FAILURE MECHANISM	CORRECTIVE ACTION			
24791	1-SHORTS, 1-AC	IN PROCESS	IN PROCESS			

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS1232L APR '99 MONITOR-CHIPPAC,KOREA

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1232L	C2	9848	DL829603AAC	8	SOIC	150	CPK (ChipPac, K
PROCESS Single Poly, Single Metal 0.8 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input style="width: 50px;" type="text" value="60%"/>	Tuse: <input style="width: 50px;" type="text" value="55 °C"/>
Ea: <input style="width: 50px;" type="text" value="0.7"/>	Vuse: <input style="width: 50px;" type="text" value="5.5 Volts"/>
β: <input style="width: 50px;" type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
24189	INFANT LIFE	125C, 7.0 VOLTS	230	48	HOUR	0
24190	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
		125C, 7.0 VOLTS	76	1000	HOUR	0
		TOTAL:	30	FAIL RATE (Fits): DEVICE HRS: 3.05E+07		0
23660	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
23661	STORAGE LIFE	125C	238	24	HOUR	0
	MOISTURE SOAK	85C/85% R.H.	238	168	HOUR	0
	CONVECTION REFLOW	235C	238	3	PASS	0
		TOTAL:				0
24188	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
24191	TEMP CYCLE	-55C TO 125C	39	300	CYCL	0
			39	1000	CYCL	0
		TOTAL:				0
24192	HAST	130C, 85%R.H.,5.5V	77	100	HOUR	0
		TOTAL:				0
24193	AUTOCLAVE	121C STEAM, UNBIASED	36	96	HOUR	0
		TOTAL:				0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS1232L APR '99 MONITOR-CHIPPAC,KOREA

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1232L	C2	9848	DL829603AAC	8	SOIC	150	CPK (ChipPac, K
PROCESS Single Poly, Single Metal 0.8 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
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Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS1233Z-10 OCT '99 MONITOR

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1233	A5	9932	DM924344ACA	3	SOT223	140	Carsem
PROCESS Single Poly, Single Metal 1.2 μm Zero tempco poly							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf: Tuse:
 Ea: Vuse:
 β:

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
24566	INFANT LIFE	125C, 7.0 VOLTS	229	48	HOUR	0
24567	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
		125C, 7.0 VOLTS	77	1000	HOUR	0
		TOTAL:			FAIL RATE (Fits): 30 DEVICE HRS: 3.07E+07	0
24563	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
24564	STORAGE LIFE	125C	233	24	HOUR	0
	MOISTURE SOAK	85C/85% R.H.	233	168	HOUR	0
	CONVECTION REFLOW	235C	233	3	PASS	0
		TOTAL:				0
24565	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
24568	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
		TOTAL:				0
24569	HAST	130C, 85%R.H.,5.5V	71	100	HOUR	0
		TOTAL:				0
24570	AUTOCLAVE	121C STEAM, UNBIASED	40	96	HOUR	0
		TOTAL:				0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS1233Z-10 OCT '99 MONITOR

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1233	A5	9932	DM924344ACA	3	SOT223	140	Carsem
PROCESS Single Poly, Single Metal 1.2 μ m Zero tempco poly							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	60%	Tuse:	55 °C
Ea:	0.7	Vuse:	5.5 Volts
β :	1		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
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Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS1233Z-10 JAN '00 Monitor

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1233	A5	9952	DM929359ABA	3	SOT223	140	Carsem
PROCESS Single Poly, Single Metal 1.2 μm Zero tempco poly							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
25036	INFANT LIFE	125C, 7.0 VOLTS	229	48	HOUR	
		TOTAL:	FAIL RATE (Fits):		DEVICE HRS: 3.84E+06	
25033	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
25034	STORAGE LIFE	125C	233	24	HOUR	
	MOISTURE SOAK	85C/85% R.H.	233	168	HOUR	
	CONVECTION REFLOW	235C	233	3	PASS	0
		TOTAL:				0
25035	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS1267-10 AUG '99 MONITOR - ANAM,PI

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1267	A1	9823	DK807766AAE-	20	TSSOP	170	ATP (Anam, PI)
PROCESS Single Poly, Single Metal 1.2 μm Poly1 Resistor							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf:	60%	Tuse:	55 °C
Ea:	0.7	Vuse:	5.5 Volts
β:	1		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
24343	INFANT LIFE	125C, 6.0 V, -4.0V	228	48	HOUR	0
24344	HIGH VOLTAGE LIFE	125C, 6.0 V, -4.0V	75	336	HOUR	0
		125C, 6.0 V, -4.0V	69	1000	HOUR	0
		TOTAL:	87	DEVICE HRS: 1.05E+07		0
24340	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
24341	STORAGE LIFE	125C	238	24	HOUR	0
	MOISTURE SOAK	85C/85% R.H.	238	168	HOUR	0
	CONVECTION REFLOW	235C	232	3	PASS	0
		TOTAL:				0
24342	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
24345	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
		TOTAL:				0
24346	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
		TOTAL:				0
24347	AUTOCLAVE	121C STEAM, UNBIASED	34	96	HOUR	0
		TOTAL:				0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS1267-10 AUG '99 MONITOR - ANAM,PI

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1267	A1	9823	DK807766AAE-	20	TSSOP	170	ATP (Anam, PI)
PROCESS Single Poly, Single Metal 1.2 μm Poly1 Resistor							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	60%	Tuse:	55 °C
Ea:	0.7	Vuse:	5.5 Volts
β:	1		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
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Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS1267-010 FEB '99 MONITOR - ANAM,PI

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1267	A1	9823	DK807766AAH	20	TSSOP	170	ATP (Anam, PI)
PROCESS Single Poly, Single Metal 1.2 µm Poly1 Resistor							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
24044	INFANT LIFE	125C, 6.0 V, -4.0V	227	48	HOUR	0
24132	HIGH VOLTAGE LIFE	125C, 6.0 V, -4.0V	77	336	HOUR	0
		125C, 6.0 V, -4.0V	77	664	HOUR	0
		TOTAL:	81	DEVICE HRS: 1.13E+07		0
23262	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
23263	STORAGE LIFE	125C	238	24	HOUR	
	MOISTURE SOAK	85C/85% R.H.	238	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	233	3	PASS	0
		TOTAL:				0
24043	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
24133	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	700	CYCL	0
		TOTAL:				0
24134	BIASED MOISTURE	85/85, 5.5 VOLTS	75	274	HOUR	0
			73	959	HOUR	0
		TOTAL:				0
24135	AUTOCLAVE	121C STEAM, UNBIASED	33	96	HOUR	0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS1267-010 FEB '99 MONITOR - ANAM,PI

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1267	A1	9823	DK807766AAH	20	TSSOP	170	ATP (Anam, PI)
PROCESS Single Poly, Single Metal 1.2 μ m Poly1 Resistor							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	60%	Tuse:	55 °C
Ea:	0.7	Vuse:	5.5 Volts
β :	1		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
TOTAL:						0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS1302 JUN '99 MONITOR-ANAM,PI

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1302	A3	9905	DK824165AAA	8	DIP	300	ATP (Anam, PI)
PROCESS Single Poly, Double Metal 0.8 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
23938	INFANT LIFE	125C, 6.0 VOLTS	230	48	HOUR	0
24513	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS	75	336	HOUR	0
		125C, 6.0 VOLTS	75	1000	HOUR	0
TOTAL:			83	DEVICE HRS: 1.11E+07		0
24514	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			39	1000	CYCL	1
TOTAL:						1
24515	BIASED MOISTURE	85/85, 5.5 VOLTS	75	274	HOUR	0
			75	959	HOUR	0
TOTAL:						0
24516	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED	36	96	HOUR	
TOTAL:						
JOB NO	FAILURE MODE	FAILURE MECHANISM	CORRECTIVE ACTION			
24514	TRICKLE CHARGE	IN PROCESS	IN PROCESS			

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS1621S JUN '99 MONITOR - ANAM,PI

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1621	A7	9915	DK815282AAB	8	SOIC	150	ATP (Anam, PI)
PROCESS Single Poly, Single Metal 0.8 μm E2PROM process							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input style="width: 50px;" type="text" value="60%"/>	Tuse: <input style="width: 50px;" type="text" value="55 °C"/>
Ea: <input style="width: 50px;" type="text" value="0.7"/>	Vuse: <input style="width: 50px;" type="text" value="5.5 Volts"/>
β: <input style="width: 50px;" type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
24321	INFANT LIFE	125C, 7.0 VOLTS	234	48	HOUR	0
24322	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
		125C, 7.0 VOLTS	77	1000	HOUR	0
TOTAL:			30	DEVICE HRS: 3.08E+07		0
24314	ULTRASOUND	J-STD-020	4			0
TOTAL:						0
24315	STORAGE LIFE	125C	241	24	HOUR	
	MOISTURE SOAK	85C/85% R.H.	241	168	HOUR	
	CONVECTION REFLOW	235C	241	3	PASS	0
TOTAL:						0
24316	PRECONDITION U/S	J-STD-020	4			0
TOTAL:						0
24323	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
24324	BIASED MOISTURE	85/85, 5.5 VOLTS	69	274	HOUR	0
			69	959	HOUR	0
TOTAL:						0
24325	WRITE CYCLE STRESS	85 C, 7.0 VOLTS	45	50	KCYC	0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS1621S JUN '99 MONITOR - ANAM,PI

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1621	A7	9915	DK815282AAB	8	SOIC	150	ATP (Anam, PI)
PROCESS Single Poly, Single Metal 0.8 μm E2PROM process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
		TOTAL:				0
24326	STORAGE LIFE	150C	44	336	HOUR	1
			44	1000	HOUR	0
		TOTAL:				1
JOB NO	FAILURE MODE	FAILURE MECHANISM	CORRECTIVE ACTION			
24326	DATA RETENTION	IN VERIFICATION	NA			

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS1621 SEP '99 MONITOR - ANAM, PI

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1621	A7	9930	DK906731AAC	8	SOIC	150	ATP (Anam, PI)
PROCESS Single Poly, Single Metal 0.8 μm E2PROM process							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input style="width: 50px;" type="text" value="60%"/>	Tuse: <input style="width: 50px;" type="text" value="55 °C"/>
Ea: <input style="width: 50px;" type="text" value="0.7"/>	Vuse: <input style="width: 50px;" type="text" value="5.5 Volts"/>
β: <input style="width: 50px;" type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
24462	INFANT LIFE	125C, 7.0 VOLTS	225	48	HOUR	0
24463	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
		125C, 7.0 VOLTS	77	1000	HOUR	0
		TOTAL:	30	FAIL RATE (Fits): DEVICE HRS: 3.07E+07		0
24459	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
24460	STORAGE LIFE	125C	241	24	HOUR	
	MOISTURE SOAK	85C/85% R.H.	241	168	HOUR	
	CONVECTION REFLOW	235C	240	3	PASS	0
		TOTAL:				0
24461	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
24464	TEMP CYCLE	-55C TO 125C	36	300	CYCL	0
			36	1000	CYCL	0
		TOTAL:				0
24465	BIASED MOISTURE	85/85, 5.5 VOLTS	63	274	HOUR	0
			62	959	HOUR	0
		TOTAL:				0
24466	WRITE CYCLE STRESS	85 C, 7.0 VOLTS	39	50	KCYC	6

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS1621 SEP '99 MONITOR - ANAM, PI

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1621	A7	9930	DK906731AAC	8	SOIC	150	ATP (Anam, PI)
PROCESS Single Poly, Single Metal 0.8 μm E2PROM process							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
TOTAL:						6
24467	STORAGE LIFE	150C	39	336	HOUR	0
			38	1000	HOUR	1
TOTAL:						1
JOB NO	FAILURE MODE	FAILURE MECHANISM	CORRECTIVE ACTION			
24466	TI_OSC (4)	WRITE CYCLE WEAR OUT	DESIGN ENHANCEMENTS: HV REGULATION, TERMINATION SCHEMES, V RAMP, TUNNEL OXIDE CONTROL			
24466	IOL (2)	WRITE CYCLE WEAR OUT	DESIGN ENHANCEMENTS: HV REGULATION, TERMINATION SCHEMES, V RAMP, TUNNEL OXIDE CONTROL			
24467	DATA RETENTION	IN VERIFICATION	NA			

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS17485 AUG '99 MONITOR,D.P-ANAM,PI.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS174855	A4	9906	DK838211AAF	24	SOIC	300	ATP (Anam, PI)
PROCESS Single Poly, Double Metal 0.8 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
24362	INFANT LIFE	125C, 7.0 VOLTS	231	48	HOUR	0
24363	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	76	336	HOUR	1
		125C, 7.0 VOLTS	76	1000	HOUR	
		TOTAL:			FAIL RATE (Fits): 66 DEVICE HRS: 3.04E+07	1
24359	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
24360	STORAGE LIFE	125C	237	24	HOUR	
	MOISTURE SOAK	30C/60% R.H.	237	144	HOUR	
	CONVECTION REFLOW	235C	235	3	PASS	0
		TOTAL:				0
24361	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
24364	TEMP CYCLE	-55C TO 125C	50	300	CYCL	0
			50	1000	CYCL	
		TOTAL:				0
24365	HAST	130C, 85%R.H.,5.5V	66	100	HOUR	
		TOTAL:				
24366	AUTOCLAVE	121C STEAM, UNBIASED	38	96	HOUR	
		TOTAL:				

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS17485 AUG '99 MONITOR,D.P-ANAM,PI.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS174855	A4	9906	DK838211AAF	24	SOIC	300	ATP (Anam, PI)
PROCESS Single Poly, Double Metal 0.8 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
JOB NO	FAILURE MODE	FAILURE MECHANISM	CORRECTIVE ACTION			
24363	IBBRAM_ZERO	IN VERIFICATION				NA

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS1803-010 NOV '98 MONITOR - HYUNDAI,K.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1803	A2	9833	DL820412AAB	16	SOIC	150	CPK (ChipPac, K
PROCESS Single Poly, Double Metal 0.8 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
23173	INFANT LIFE	125C, 7.0 VOLTS	234	48	HOUR	0
23923	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
		125C, 7.0 VOLTS	77	1000	HOUR	0
		TOTAL:			FAIL RATE (Fits): 30 DEVICE HRS: 3.08E+07	0
22797	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
22798	STORAGE LIFE	125C	238	24	HOUR	0
	MOISTURE SOAK	85C/85% R.H.	238	168	HOUR	0
	SOLDER HEAT	HTC VAPOR PHASE	238	3	PASS	0
		TOTAL:				0
23172	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
23924	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
		TOTAL:				0
23925	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			77	959	HOUR	0
		TOTAL:				0
23926	AUTOCLAVE	121C STEAM, UNBIASED	40	96	HOUR	0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS1803-010 NOV '98 MONITOR - HYUNDAI,K.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1803	A2	9833	DL820412AAB	16	SOIC	150	CPK (ChipPac, K
PROCESS Single Poly, Double Metal 0.8 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
TOTAL:						0

Empty "No of Fails" TOTAL implies that Material is still in stess

RELIABILITY MONITOR

DS1803-010 FEB '99 MONITOR - HYUNDAI,K.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1803	A2	9835	DL818111AAB	16	SOIC	150	CPK (ChipPac, K
PROCESS Single Poly, Double Metal 0.8 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
23928	INFANT LIFE	125C, 7.0 VOLTS	232	48	HOUR	0
24003	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	76	336	HOUR	1
		125C, 7.0 VOLTS	76	1000	HOUR	0
		TOTAL:			FAIL RATE (Fits): 66 DEVICE HRS: 3.04E+07	1
23274	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
23275	STORAGE LIFE	125C	238	24	HOUR	0
	MOISTURE SOAK	85C/85% R.H.	238	168	HOUR	0
	SOLDER HEAT	HTC VAPOR PHASE	238	3	PASS	0
		TOTAL:				0
23927	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
24004	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
		TOTAL:				0
24005	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			77	959	HOUR	0
		TOTAL:				0
24006	AUTOCLAVE	121C STEAM, UNBIASED	36	96	HOUR	1

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS1803-010 FEB '99 MONITOR - HYUNDAI,K.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1803	A2	9835	DL818111AAB	16	SOIC	150	CPK (ChipPac, K
PROCESS Single Poly, Double Metal 0.8 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
TOTAL:						1
JOB NO	FAILURE MODE	FAILURE MECHANISM	CORRECTIVE ACTION			
24003	CONTINUITY	EOS	NA			
24006	CONTINUITY	IN FA	IN PROCESS			

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS1803-010 AUG '99 MONITOR -ANAM,PI.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1803	A2	9909	DK830515AAB	16	SOIC	150	ATP (Anam, PI)
PROCESS Single Poly, Double Metal 0.8 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input style="width: 50px;" type="text" value="60%"/>	Tuse: <input style="width: 50px;" type="text" value="55 °C"/>
Ea: <input style="width: 50px;" type="text" value="0.7"/>	Vuse: <input style="width: 50px;" type="text" value="5.5 Volts"/>
β: <input style="width: 50px;" type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
24370	INFANT LIFE	125C, 7.0 VOLTS	234	48	HOUR	0
24371	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
		125C, 7.0 VOLTS	77	1000	HOUR	0
		TOTAL:	30	DEVICE HRS: 3.08E+07		0
24367	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
24368	STORAGE LIFE	125C	238	24	HOUR	0
	MOISTURE SOAK	85C/85% R.H.	238	168	HOUR	0
	CONVECTION REFLOW	235C	238	3	PASS	0
		TOTAL:				0
24369	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
24372	TEMP CYCLE	-55C TO 125C	39	300	CYCL	0
			39	1000	CYCL	0
		TOTAL:				0
24373	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			77	959	HOUR	0
		TOTAL:				0
24374	AUTOCLAVE	121C STEAM, UNBIASED	36	96	HOUR	0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS1803-010 AUG '99 MONITOR -ANAM,PI.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1803	A2	9909	DK830515AAB	16	SOIC	150	ATP (Anam, PI)
PROCESS Single Poly, Double Metal 0.8 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	60%	Tuse:	55 °C
Ea:	0.7	Vuse:	5.5 Volts
β:	1		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
TOTAL:						0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS1803-010 NOV '99 MONITOR

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1803	A2	9923	DK913631AAA	16	SOIC	150	ATP (Anam, PI)
PROCESS Single Poly, Double Metal 0.8 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf: Tuse:
 Ea: Vuse:
 β:

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
24738	INFANT LIFE	125C, 7.0 VOLTS	224	48	HOUR	0
24739	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
		125C, 7.0 VOLTS	77	1000	HOUR	0
		TOTAL:			FAIL RATE (Fits): 30 DEVICE HRS: 3.07E+07	0
24735	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
24736	STORAGE LIFE	125C	238	24	HOUR	0
	MOISTURE SOAK	85C/85% R.H.	238	168	HOUR	0
	CONVECTION REFLOW	235C	228	3	PASS	0
		TOTAL:				0
24737	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
24740	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
		TOTAL:				0
24741	BIASED MOISTURE	85/85, 5.5 VOLTS	67	274	HOUR	0
			67	959	HOUR	0
		TOTAL:				0
24742	AUTOCLAVE	121C STEAM, UNBIASED	40	96	HOUR	0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS1803-010 NOV '99 MONITOR

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1803	A2	9923	DK913631AAA	16	SOIC	150	ATP (Anam, PI)

PROCESS Single Poly, Double Metal 0.8 μm Standard Process

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
TOTAL:						0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS1869S MAR '99 MONITOR - NSEB

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1869	A3	9829	DJ821534ABB	8	SOIC	208	NSEB
PROCESS Single Poly, Single Metal 1.2 μm E2PROM process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf: Tuse:
 Ea: Vuse:
 β:

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
23440	INFANT LIFE	125C, 7.0 VOLTS	237	48	HOUR	0
24022	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	76	336	HOUR	0
		125C, 7.0 VOLTS	76	1000	HOUR	0
TOTAL:			30	DEVICE HRS: 3.05E+07		0
23360	ULTRASOUND	J-STD-020	4			0
TOTAL:						0
23361	STORAGE LIFE	125C	241	24	HOUR	
	MOISTURE SOAK	85C/85% R.H.	241	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	241	3	PASS	0
TOTAL:						0
23439	PRECONDITION U/S	J-STD-020	4			0
TOTAL:						0
24023	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
24024	BIASED MOISTURE	85/85, 5.5 VOLTS	70	274	HOUR	0
			65	959	HOUR	0
TOTAL:						0
24025	WRITE CYCLE STRESS	85 C, 7.0 VOLTS	50	25	KCYC	0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS1869S MAR '99 MONITOR - NSEB

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1869	A3	9829	DJ821534ABB	8	SOIC	208	NSEB
PROCESS Single Poly, Single Metal 1.2 μ m E2PROM process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	60%	Tuse:	55 °C
Ea:	0.7	Vuse:	5.5 Volts
β :	1		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
		TOTAL:				0
24288	STORAGE LIFE	150C	46	336	HOUR	0
			45	1000	HOUR	0
		TOTAL:				0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS1869 JUN '99 MONITOR - NSEB

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1869	A3	9836	DJ824252AAC	8	SOIC	208	NSEB
PROCESS Single Poly, Single Metal 1.2 μm E2PROM process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf: Tuse:
 Ea: Vuse:
 β:

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
24032	INFANT LIFE	125C, 7.0 VOLTS	230	48	HOUR	0
24228	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	70	336	HOUR	0
		125C, 7.0 VOLTS	66	1000	HOUR	0
		TOTAL:	33	DEVICE HRS: 2.74E+07		0
23944	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
23945	STORAGE LIFE	125C	241	24	HOUR	0
	MOISTURE SOAK	85C/85% R.H.	241	168	HOUR	0
	SOLDER HEAT	HTC VAPOR PHASE	234	3	PASS	0
		TOTAL:				0
24031	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
24229	TEMP CYCLE	-55C TO 125C	39	300	CYCL	0
			39	1000	CYCL	0
		TOTAL:				0
24230	BIASED MOISTURE	85/85, 5.5 VOLTS	63	274	HOUR	0
			61	959	HOUR	0
		TOTAL:				0
24231	WRITE CYCLE STRESS	85 C, 7.0 VOLTS	50	25	KCYC	0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS1869 JUN '99 MONITOR - NSEB

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1869	A3	9836	DJ824252AAC	8	SOIC	208	NSEB
PROCESS Single Poly, Single Metal 1.2 μ m E2PROM process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	60%	Tuse:	55 °C
Ea:	0.7	Vuse:	5.5 Volts
β :	1		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
		TOTAL:				0
24252	STORAGE LIFE	150C	50	336	HOUR	0
			50	1000	HOUR	0
		TOTAL:				0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS1869 SEP '99 MONITOR - NSEB

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1869	A3	9907	DJ824247ABA	8	SOIC	208	NSEB
PROCESS Single Poly, Single Metal 1.2 μm E2PROM process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf: Tuse:
 Ea: Vuse:
 β:

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
24441	INFANT LIFE	125C, 7.0 VOLTS	213	48	HOUR	0
24442	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	75	336	HOUR	0
		125C, 7.0 VOLTS	74	1000	HOUR	0
		TOTAL:			FAIL RATE (Fits): 31 DEVICE HRS: 2.95E+07	0
24438	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
24439	STORAGE LIFE	125C	241	24	HOUR	
	MOISTURE SOAK	85C/85% R.H.	241	168	HOUR	
	CONVECTION REFLOW	235C	235	3	PASS	0
		TOTAL:				0
24440	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
24443	TEMP CYCLE	-55C TO 125C	35	300	CYCL	0
			35	1000	CYCL	0
		TOTAL:				0
24444	BIASED MOISTURE	85/85, 5.5 VOLTS	53	274	HOUR	0
			53	959	HOUR	0
		TOTAL:				0
24445	WRITE CYCLE STRESS	85 C, 7.0 VOLTS	46	25	KCYC	0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS1869 SEP '99 MONITOR - NSEB

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1869	A3	9907	DJ824247ABA	8	SOIC	208	NSEB
PROCESS Single Poly, Single Metal 1.2 μ m E2PROM process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	60%	Tuse:	55 °C
Ea:	0.7	Vuse:	5.5 Volts
β :	1		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
		TOTAL:				0
24446	STORAGE LIFE	150C	46	336	HOUR	0
			46	1000	HOUR	0
		TOTAL:				0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS2108 AUG '99 MONITOR,D.P-ANAM,PI.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2108	B7	9922	DK913650AAF	24	SOIC	300	ATP (Anam, PI)
PROCESS Single Poly, Single Metal 5.0 μm Negative zero tempco poly							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
24386	INFANT LIFE	125C, 6.0 VOLTS	234	48	HOUR	0
24387	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS	77	336	HOUR	0
		125C, 6.0 VOLTS	77	1000	HOUR	0
		TOTAL:	81	DEVICE HRS: 1.13E+07		0
24383	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
24384	STORAGE LIFE	125C	238	24	HOUR	0
	MOISTURE SOAK	30C/60% R.H.	238	144	HOUR	0
	CONVECTION REFLOW	235C	238	3	PASS	0
		TOTAL:				0
24385	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
24388	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
		TOTAL:				0
24389	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			77	959	HOUR	0
		TOTAL:				0
24390	AUTOCLAVE	121C STEAM, UNBIASED	40	96	HOUR	0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS2108 AUG '99 MONITOR,D.P-ANAM,PI.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2108	B7	9922	DK913650AAF	24	SOIC	300	ATP (Anam, PI)
PROCESS Single Poly, Single Metal 5.0 μm Negative zero tempco poly							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	60%	Tuse:	55 °C
Ea:	0.7	Vuse:	5.5 Volts
β:	1		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
TOTAL:						0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS2108 FEB '00 MONITOR, D.P.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2108	B7	9951	DK940069AAC	24	SOIC	300	ASI (Anam, K)
PROCESS Single Poly, Single Metal 5.0 μm Negative zero tempco poly							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
25106	INFANT LIFE	125C, 6.0 VOLTS	229	48	HOUR	0
25107	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS	77	336	HOUR	0
TOTAL:			193	FAIL RATE (Fits): DEVICE HRS: 4.74E+06		0
25103	ULTRASOUND	J-STD-020	4			0
TOTAL:						0
25104	STORAGE LIFE	125C	238	24	HOUR	0
	MOISTURE SOAK	30C/60% R.H.	238	144	HOUR	0
	CONVECTION REFLOW	235C	238	3	PASS	0
TOTAL:						0
25105	PRECONDITION U/S	J-STD-020	4			0
TOTAL:						0
25108	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
TOTAL:						0
25110	AUTOCLAVE	121C STEAM, UNBIASED	35	96	HOUR	0
TOTAL:						0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS2109S MAR '99 MONITOR-CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2109	A7	9839	DM812688AAA	28	SOIC	300	Carsem
PROCESS Single Poly, Single Metal 0.8 μm Negative zero tempco poly							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf:	60%	Tuse:	55 °C
Ea:	0.7	Vuse:	5.5 Volts
β:	1		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
23723	INFANT LIFE	125C, 7.0 VOLTS	228	48	HOUR	1
23832	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
		125C, 7.0 VOLTS	74	1000	HOUR	0
		TOTAL:			FAIL RATE (Fits): 67 DEVICE HRS: 3.00E+07	1
23363	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
23364	STORAGE LIFE	125C	237	24	HOUR	0
	MOISTURE SOAK	85C/85% R.H.	237	168	HOUR	0
	CONVECTION REFLOW	235C	237	3	PASS	0
		TOTAL:				0
23722	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
23833	TEMP CYCLE	-55C TO 125C	50	300	CYCL	0
			50	1000	CYCL	0
		TOTAL:				0
23834	HAST	130C, 85%R.H.,5.5V	66	100	HOUR	0
		TOTAL:				0
23835	AUTOCLAVE	121C STEAM, UNBIASED	31	96	HOUR	4
		TOTAL:				4

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS2109S MAR '99 MONITOR-CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2109	A7	9839	DM812688AAA	28	SOIC	300	Carsem
PROCESS Single Poly, Single Metal 0.8 μm Negative zero tempco poly							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	60%	Tuse:	55 °C
Ea:	0.7	Vuse:	5.5 Volts
β:	1		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
JOB NO	FAILURE MODE	FAILURE MECHANISM	CORRECTIVE ACTION			
23723	TERM RESISTANCE	IN FA 990219	IN PROCESS			
23835	CONTINUITY (4)	IN PROCESS	IN PROCESS			

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS2109S JUN '99 MONITOR - CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2109	A7	9839	DM811523AAA	28	SOIC	300	Carsem

JOB_NO	DESCRIPTION	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
23947	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
23948	STORAGE LIFE	125C	237	24	HOUR	
	MOISTURE SOAK	85C/85% R.H.	237	168	HOUR	
	CONVECTION REFLOW	235C	237	3	PASS	0
		TOTAL:				0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS2109 DEC '99 MONITOR

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2109	A7	9842	DM812689AAA	28	SOIC	300	Carsem
PROCESS Single Poly, Single Metal 0.8 μm Negative zero tempco poly							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	60%	Tuse:	55 °C
Ea:	0.7	Vuse:	5.5 Volts
β:	1		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
24808	INFANT LIFE	125C, 7.0 VOLTS	230	48	HOUR	2
		TOTAL:	805	FAIL RATE (Fits):	3.86E+06	2
24805	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
24806	STORAGE LIFE	125C	237	24	HOUR	
	MOISTURE SOAK	85C/85% R.H.	237	168	HOUR	
	CONVECTION REFLOW	235C	236	3	PASS	0
		TOTAL:				0
24807	PRECONDITION U/S	J-STD-020	3			1
		TOTAL:				1

JOB NO	FAILURE MODE	FAILURE MECHANISM	CORRECTIVE ACTION
24807	DIE DELAMINATION	ONE SAMPLE W/100% DIE DELAM/ELECTRICALLY GOOD	NONE, 237 PRODUCTS WERE PRECONDITIONED TO LEVEL ONE W/NO FAILURES. SUBSEQUENT STRESSING IN PROCESS.
24808	TERM RESISTANCE	GATE OXIDE	SEVERAL EVALUATIONS ARE IN PROCESS TO IMPROVE GATE OXIDE PERFORMANCE

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS2118M MAR '99 MONITOR,D.P.-ANAM,K.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2118M	A4	9904	DN844402AAC	36	SSOP	300	ASI (Anam, K)
PROCESS Single Poly, Double Metal 0.8 μm Negative zero tempco poly							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
23526	INFANT LIFE	125C, 6.0 VOLTS	234	48	HOUR	0
23600	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS	77	336	HOUR	0
		125C, 6.0 VOLTS	76	1000	HOUR	1
TOTAL:			180	DEVICE HRS: 1.13E+07		1
23365	ULTRASOUND	J-STD-020	4			0
TOTAL:						0
23366	STORAGE LIFE	125C	238	24	HOUR	
	MOISTURE SOAK	30C/60% R.H.	238	240	HOUR	
	CONVECTION REFLOW	235C	238	3	PASS	0
TOTAL:						0
23525	PRECONDITION U/S	J-STD-020	4			0
TOTAL:						0
23601	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
23602	HAST	130C, 85%R.H.,5.5V	76	100	HOUR	0
TOTAL:						0
23603	AUTOCLAVE	121C STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS2118M MAR '99 MONITOR,D.P.-ANAM,K.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2118M	A4	9904	DN844402AAC	36	SSOP	300	ASI (Anam, K)
PROCESS Single Poly, Double Metal 0.8 μm Negative zero tempco poly							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
JOB NO	FAILURE MODE	FAILURE MECHANISM	CORRECTIVE ACTION			
23600	RDM-LVD	GATE OXIDE	SEVERAL EVALUATIONS ARE IN PROCESS TO IMPROVE GATE OXIDE PERFORMANCE			

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS2118M JUN '99 MONITOR,D.P. ANAM,K.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2118M	A4	9912	DN848138AAA	36	SSOP	300	ASI (Anam, K)
PROCESS Single Poly, Double Metal 0.8 μm Negative zero tempco poly							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf:	60%	Tuse:	55 °C
Ea:	0.7	Vuse:	5.5 Volts
β:	1		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
24038	INFANT LIFE	125C, 6.0 VOLTS	234	48	HOUR	0
24070	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS	76	336	HOUR	0
		125C, 6.0 VOLTS	72	1000	HOUR	0
		TOTAL:	84	DEVICE HRS: 1.09E+07		0
23949	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
23950	STORAGE LIFE	125C	238	24	HOUR	0
	MOISTURE SOAK	30C/60% R.H.	238	240	HOUR	0
	CONVECTION REFLOW	235C	238	3	PASS	0
		TOTAL:				0
24037	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
24071	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
		TOTAL:				0
24072	HAST	130C, 85%R.H.,5.5V	77	100	HOUR	0
		TOTAL:				0
24073	AUTOCLAVE	121C STEAM, UNBIASED	40	96	HOUR	0
		TOTAL:				0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS2118M JUN '99 MONITOR,D.P. ANAM,K.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2118M	A4	9912	DN848138AAA	36	SSOP	300	ASI (Anam, K)

PROCESS Single Poly, Double Metal 0.8 μm Negative zero tempco poly

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	60%	Tuse:	55 °C
Ea:	0.7	Vuse:	5.5 Volts
β:	1		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
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RELIABILITY MONITOR

DS2118M SEP '99 MONITOR, D.P. Carsem

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2118M	A4	9919	DM905555AAD	36	SSOP	300	Carsem
PROCESS Single Poly, Double Metal 0.8 μm Negative zero tempco poly							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
24453	INFANT LIFE	125C, 6.0 VOLTS	231	48	HOUR	0
24454	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS	75	336	HOUR	0
		125C, 6.0 VOLTS	75	1000	HOUR	0
		TOTAL:	83	DEVICE HRS: 1.11E+07		0
24450	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
24451	STORAGE LIFE	125C	238	24	HOUR	0
	MOISTURE SOAK	30C/60% R.H.	238	240	HOUR	0
	CONVECTION REFLOW	235C	236	3	PASS	0
		TOTAL:				0
24452	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
24455	TEMP CYCLE	-55C TO 125C	39	300	CYCL	0
			39	1000	CYCL	0
		TOTAL:				0
24456	HAST	130C, 85%R.H.,5.5V	77	100	HOUR	0
		TOTAL:				0
24457	AUTOCLAVE	121C STEAM, UNBIASED	37	96	HOUR	0
		TOTAL:				0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS2118M SEP '99 MONITOR, D.P. Carsem

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2118M	A4	9919	DM905555AAD	36	SSOP	300	Carsem
PROCESS Single Poly, Double Metal 0.8 μm Negative zero tempco poly							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	60%	Tuse:	55 °C
Ea:	0.7	Vuse:	5.5 Volts
β:	1		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
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Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS2153Q MAR '99 MONITOR,D.P.-ANAM,K.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2153	A7	9901	DN819185AAB	44	LCC	650	ASI (Anam, K)
PROCESS Double Poly, Single Metal 0.8 μm N Depletion Capacitor							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
23622	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS	77	1000	HOUR	
TOTAL:			FAIL RATE (Fits):		DEVICE HRS: 9.89E+06	
23367	ULTRASOUND	J-STD-020	4			0
TOTAL:			0			
23368	STORAGE LIFE	125C	241	24	HOUR	
	MOISTURE SOAK	30C/60% R.H.	241	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	241	3	PASS	0
TOTAL:			0			
23621	PRECONDITION U/S	J-STD-020	4			0
TOTAL:			0			
23623	TEMP CYCLE	-55C TO 125C	60	1000	CYCL	
TOTAL:			0			
23624	AUTOCLAVE	121C STEAM, UNBIASED	100	96	HOUR	
TOTAL:			0			

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS2154 JUN '99 MONITOR,D.P.-ANAM,K.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2154	A2	9914	DN901043AAC	100	LQFP	550	ASI (Anam, K)
PROCESS Double Poly, Double Met 0.8 μm N Depletion Capacitor							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf:	60%	Tuse:	55 °C
Ea:	0.7	Vuse:	5.5 Volts
β:	1		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
24426	INFANT LIFE	125C, 7.0 VOLTS	230	48	HOUR	0
24427	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	73	336	HOUR	0
		125C, 7.0 VOLTS	69	1000	HOUR	4
		TOTAL:	184	FAIL RATE (Fits): DEVICE HRS: 2.84E+07		4
23951	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
23952	STORAGE LIFE	125C	238	24	HOUR	0
	MOISTURE SOAK	30C/60% R.H.	238	144	HOUR	0
	CONVECTION REFLOW	235C	235	3	PASS	0
		TOTAL:				0
24425	PRECONDITION U/S	J-STD-020	4			0
	EXTERNAL VISUAL	MIL-STD-883-2009	4			0
		TOTAL:				0
24428	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
		TOTAL:				0
24429	HAST	130C, 85%R.H.,5.5V	9	100	HOUR	0
		TOTAL:				0
24430	HAST, NO BIAS	130C, 85% R.H.	48	100	HOUR	0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS2154 JUN '99 MONITOR,D.P.-ANAM,K.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2154	A2	9914	DN901043AAC	100	LQFP	550	ASI (Anam, K)
PROCESS Double Poly, Double Met 0.8 μm N Depletion Capacitor							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	60%	Tuse:	55 °C
Ea:	0.7	Vuse:	5.5 Volts
β:	1		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
TOTAL:						0
JOB NO	FAILURE MODE	FAILURE MECHANISM	CORRECTIVE ACTION			
24427	JITTER TOLERANCE (3)	IN VERIFICATION	NA			
24427	CONTINUITY	IN VERIFICATION	NA			

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS2165Q OCT '98 MONITOR - ANAM,K.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2165	B1	9837	DN811583AAB	28	LCC	450	ASI (Anam, K)
PROCESS Single Poly, Single Metal 1.2 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf: <input style="width: 50px;" type="text" value="60%"/>	Tuse: <input style="width: 50px;" type="text" value="55 °C"/>
Ea: <input style="width: 50px;" type="text" value="0.7"/>	Vuse: <input style="width: 50px;" type="text" value="5.5 Volts"/>
β: <input style="width: 50px;" type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
22757	INFANT LIFE	125C, 7.0 VOLTS	235	48	HOUR	0
23168	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
		125C, 7.0 VOLTS	76	1000	HOUR	0
		TOTAL:	30	FAIL RATE (Fits): DEVICE HRS: 3.06E+07		0
22680	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
22681	TEMP CYCLE	-55C TO 125C	241	10	CYCL	
	STORAGE LIFE	125C	241	24	HOUR	
	MOISTURE SOAK	30C/60% R.H.	241	144	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	240	3	PASS	0
		TOTAL:				0
22756	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
23169	TEMP CYCLE	-55C TO 125C	60	300	CYCL	0
			60	1000	CYCL	0
		TOTAL:				0
23170	HAST	130C, 85%R.H.,5.5V	60	100	HOUR	0
		TOTAL:				0
23171	AUTOCLAVE	121C STEAM, UNBIASED	38	96	HOUR	0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS2165Q OCT '98 MONITOR - ANAM,K.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2165	B1	9837	DN811583AAB	28	LCC	450	ASI (Anam, K)
PROCESS Single Poly, Single Metal 1.2 μ m Standard Process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	60%	Tuse:	55 °C
Ea:	0.7	Vuse:	5.5 Volts
β :	1		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
TOTAL:						0
JOB NO	FAILURE MODE	FAILURE MECHANISM	CORRECTIVE ACTION			
23168	SHORT XOUT	HANDLING DAMAGE	NA			

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS2180A APR '99 MONITOR - ANAM,K.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2180	B3	9850	DN839402AAC	44	LCC	650	ASI (Anam, K)
PROCESS Single Poly, Single Metal 2.0 μm Pfield							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf: <input style="width: 50px;" type="text" value="60%"/>	Tuse: <input style="width: 50px;" type="text" value="55 °C"/>
Ea: <input style="width: 50px;" type="text" value="0.7"/>	Vuse: <input style="width: 50px;" type="text" value="5.5 Volts"/>
β: <input style="width: 50px;" type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
23775	INFANT LIFE	125C, 7.0 VOLTS	235	48	HOUR	0
23879	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
		125C, 7.0 VOLTS	77	1000	HOUR	0
		TOTAL:	30	FAIL RATE (Fits): DEVICE HRS: 3.08E+07		0
23667	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
23668	TEMP CYCLE	-55C TO 125C	241	10	CYCL	0
	STORAGE LIFE	125C	241	24	HOUR	0
	MOISTURE SOAK	30C/60% R.H.	241	144	HOUR	0
	SOLDER HEAT	HTC VAPOR PHASE	241	3	PASS	0
		TOTAL:				0
23774	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
23880	TEMP CYCLE	-55C TO 125C	60	300	CYCL	0
			60	1000	CYCL	0
		TOTAL:				0
23881	HAST	130C, 85%R.H.,5.5V	60	100	HOUR	0
		TOTAL:				0
23882	AUTOCLAVE	121C STEAM, UNBIASED	37	96	HOUR	0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS2180A APR '99 MONITOR - ANAM,K.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2180	B3	9850	DN839402AAC	44	LCC	650	ASI (Anam, K)
PROCESS Single Poly, Single Metal 2.0 μm Pfield							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	60%	Tuse:	55 °C
Ea:	0.7	Vuse:	5.5 Volts
β:	1		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
TOTAL:						0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS21S07 FEB '99 MONITOR - ANAM,PI

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS21S07A	B3	9851	DK821542AAF	20	TSSOP	170	ATP (Anam, PI)

JOB_NO	DESCRIPTION	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
23276	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
23277	STORAGE LIFE	125C	238	24	HOUR	
	MOISTURE SOAK	85C/85% R.H.	238	168	HOUR	
	CONVECTION REFLOW	235C	238	3	PASS	0
		TOTAL:				0
24208	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
24211	TEMP CYCLE	-55C TO 125C	35	300	CYCL	0
		-55C TO 125C	35	1000	CYCL	0
		TOTAL:				0
24212	BIASED MOISTURE	85/85, 5.5 VOLTS	76	274	HOUR	0
		85/85, 5.5 VOLTS	63	959	HOUR	0
		TOTAL:				0
24213	AUTOCLAVE	121C STEAM, UNBIASED	26	96	HOUR	0
		TOTAL:				0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS21S07 NOV '99 MONITOR

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS21S07A	F	9908	DK836680AAF	20	TSSOP	170	ATP (Anam, PI)
PROCESS Single Poly, Single Metal 0.8 μm Negative zero tempco poly							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
24730	INFANT LIFE	125C, 7.0 VOLTS	231	48	HOUR	0
24731	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
		125C, 7.0 VOLTS	77	1000	HOUR	0
		TOTAL:			FAIL RATE (Fits): 30 DEVICE HRS: 3.08E+07	0
24727	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
24728	STORAGE LIFE	125C	238	24	HOUR	0
	MOISTURE SOAK	85C/85% R.H.	238	168	HOUR	0
	CONVECTION REFLOW	235C	235	3	PASS	0
		TOTAL:				0
24729	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
24732	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
		TOTAL:				0
24733	BIASED MOISTURE	85/85, 5.5 VOLTS	73	274	HOUR	0
			73	959	HOUR	0
		TOTAL:				0
24734	AUTOCLAVE	121C STEAM, UNBIASED	40	96	HOUR	0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS21S07 NOV '99 MONITOR

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS21S07A	F	9908	DK836680AAF	20	TSSOP	170	ATP (Anam, PI)
PROCESS Single Poly, Single Metal 0.8 μm Negative zero tempco poly							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	60%	Tuse:	55 °C
Ea:	0.7	Vuse:	5.5 Volts
β:	1		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
TOTAL:						0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS21S07 AUG '99 MONITOR - CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS21S07A	F	9913	DM828145AAA	20	TSSOP	170	Carsem S
PROCESS Single Poly, Single Metal 0.8 μm Negative zero tempco poly							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf: Tuse:
 Ea: Vuse:
 β:

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
24378	INFANT LIFE	125C, 7.0 VOLTS	229	48	HOUR	0
24379	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
		125C, 7.0 VOLTS	77	1000	HOUR	0
		TOTAL:			FAIL RATE (Fits): 30 DEVICE HRS: 3.07E+07	0
24375	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
24376	STORAGE LIFE	125C	238	24	HOUR	0
	MOISTURE SOAK	85C/85% R.H.	238	168	HOUR	0
	CONVECTION REFLOW	235C	238	3	PASS	0
		TOTAL:				0
24377	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
24380	TEMP CYCLE	-55C TO 125C	38	300	CYCL	0
			38	1000	CYCL	0
		TOTAL:				0
24381	BIASED MOISTURE	85/85, 5.5 VOLTS	70	274	HOUR	0
			70	959	HOUR	0
		TOTAL:				0
24382	AUTOCLAVE	121C STEAM, UNBIASED	40	96	HOUR	0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS21S07 AUG '99 MONITOR - CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS21S07A	F	9913	DM828145AAA	20	TSSOP	170	Carsem S
PROCESS Single Poly, Single Metal 0.8 μm Negative zero tempco poly							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	60%	Tuse:	55 °C
Ea:	0.7	Vuse:	5.5 Volts
β:	1		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
TOTAL:						0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS21S07 FEB '00 MONITOR

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS21S07A	F	9937	DK926747AAP	20	TSSOP	170	ATP (Anam, PI)
PROCESS Single Poly, Single Metal 0.8 μm Negative zero tempco poly							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	60%	Tuse:	55 °C
Ea:	0.7	Vuse:	5.5 Volts
β:	1		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
25098	INFANT LIFE	125C, 7.0 VOLTS	234	48	HOUR	
		TOTAL:			FAIL RATE (Fits):	DEVICE HRS: 3.92E+06
25095	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
25096	STORAGE LIFE	125C	238	24	HOUR	
	MOISTURE SOAK	85C/85% R.H.	238	168	HOUR	
	CONVECTION REFLOW	235C	238	3	PASS	0
		TOTAL:				0
25097	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS2401 DEC '99 MONITOR

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2401	C2	9943	DM920572AAA	3	TO92	180	Carsem
PROCESS Single Poly, Single Metal 0.6 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	60%	Tuse:	55 °C
Ea:	0.7	Vuse:	5.5 Volts
β:	1		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
24813	INFANT LIFE	125C, 6.0 VOLTS	250	48	HOUR	0
24814	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS	77	336	HOUR	0
		125C, 6.0 VOLTS	77	1000	HOUR	0
TOTAL:			80	DEVICE HRS: 1.14E+07		0
24815	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
24816	HAST	130C, 85%R.H.,5.5V	74	100	HOUR	0
TOTAL:						0
24817	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS2434 NOV '99 MONITOR

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2434	D1	9851	DM833262AAA	3	TO226 (PR35)	350	Carsem
PROCESS Single Poly, Single Metal 0.8 μm E2PROM process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	60%	Tuse:	55 °C
Ea:	0.7	Vuse:	5.5 Volts
β:	1		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
24712	INFANT LIFE	125C, 7.0 VOLTS	237	48	HOUR	0
24713	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
		125C, 7.0 VOLTS	74	1000	HOUR	3
TOTAL:			FAIL RATE (Fits): 138	DEVICE HRS: 3.02E+07		3
24714	TEMP CYCLE	-55C TO 125C	50	300	CYCL	0
			50	1000	CYCL	0
TOTAL:						0
24715	HAST	130C, 85%R.H.,5.5V	70	100	HOUR	0
TOTAL:						0
24716	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0
JOB NO	FAILURE MODE	FAILURE MECHANISM	CORRECTIVE ACTION			
24713	ICC STANDBY (2)	IN VERIFICATION	NA			
24713	MEMORY HI/LO	IN VERIFICATION	NA			

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS2502 MAR '99 MONITOR-CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2502	C2	9913	DM842206ALB	8	SOIC	150	Carsem S
PROCESS Double Poly, Single Metal 0.6 μm EPROM process							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: Tuse:
Ea: Vuse:
β:

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
24153	INFANT LIFE	125C, 6.0 VOLTS	222	48	HOUR	0
24261	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS	77	336	HOUR	0
		125C, 6.0 VOLTS	77	1000	HOUR	0
		TOTAL:	81	DEVICE HRS: 1.13E+07		0
23635	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
23636	STORAGE LIFE	125C	238	24	HOUR	0
	MOISTURE SOAK	85C/85% R.H.	238	168	HOUR	0
	VAPOR PHASE REFLOW	217C	238	3	PASS	0
		TOTAL:				0
24152	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
24262	TEMP CYCLE	-55C TO 125C	34	300	CYCL	0
			34	1000	CYCL	0
		TOTAL:				0
24263	BIASED MOISTURE	85/85, 5.5 VOLTS	76	274	HOUR	0
			74	959	HOUR	0
		TOTAL:				0
24264	STORAGE LIFE	150C	34	336	HOUR	0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS2502 MAR '99 MONITOR-CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2502	C2	9913	DM842206ALB	8	SOIC	150	Carsem S
PROCESS Double Poly, Single Metal 0.6 μ m EPROM process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	60%	Tuse:	55 °C
Ea:	0.7	Vuse:	5.5 Volts
β :	1		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
			34	1000	HOUR	0
		TOTAL:				0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS2502 JUN '99 MONITOR - CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2502	C2	9915	DM846764AAA	8	SOIC	150	Carsem S
PROCESS Double Poly, Single Metal 0.6 μm EPROM process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf: Tuse:
 Ea: Vuse:
 β:

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
24169	INFANT LIFE	125C, 6.0 VOLTS	229	48	HOUR	0
24174	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS	77	336	HOUR	0
		125C, 6.0 VOLTS	77	1000	HOUR	0
		TOTAL:	81	DEVICE HRS: 1.13E+07		0
23957	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
23958	STORAGE LIFE	125C	238	24	HOUR	0
	MOISTURE SOAK	85C/85% R.H.	238	168	HOUR	0
	VAPOR PHASE REFLOW	217C	236	3	PASS	0
		TOTAL:				0
24168	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
24175	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
		TOTAL:				0
24176	BIASED MOISTURE	85/85, 5.5 VOLTS	75	274	HOUR	0
			75	959	HOUR	0
		TOTAL:				0
24177	STORAGE LIFE	150C	37	336	HOUR	0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS2502 JUN '99 MONITOR - CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2502	C2	9915	DM846764AAA	8	SOIC	150	Carsem S
PROCESS Double Poly, Single Metal 0.6 μm EPROM process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	60%	Tuse:	55 °C
Ea:	0.7	Vuse:	5.5 Volts
β:	1		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
			37	1000	HOUR	0
TOTAL:						0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS2502 APR '99 MONITOR - CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2502	C2	9845	DM821484AAC	6	TSOC	150	Carsem

JOB_NO	DESCRIPTION	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
23669	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
23670	STORAGE LIFE	125C	151	24	HOUR	
	MOISTURE SOAK	85C/85% R.H.	151	168	HOUR	
	VAPOR PHASE REFLOW	217C	150	3	PASS	0
		TOTAL:				0
24265	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
24266	TEMP CYCLE	-55C TO 125C	77	300	CYCL	0
		-55C TO 125C	75	1000	CYCL	0
		TOTAL:				0
24267	AUTOCLAVE	121C STEAM, UNBIASED	69	96	HOUR	0
		TOTAL:				0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS2502 JAN '00 MONITOR

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2502	C3	9930	DH917304BAA	6	TSOC	150	CPS (ChipPac, C

JOB_NO	DESCRIPTION	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
25050	STORAGE LIFE	125C	151	24	HOUR	
	MOISTURE SOAK	85C/85% R.H.	151	168	HOUR	
	CONVECTION REFLOW	235C	147	3	PASS	0
		TOTAL:				0
25051	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
25052	TEMP CYCLE	-55C TO 125C	77	300	CYCL	0
		TOTAL:				0
25053	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED	64	96	HOUR	0
		TOTAL:				0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS5002 OCT '99 MONITOR

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS5002	C4	9931	DM849386AAE	80	MQFP	550	Carsem
PROCESS Single Poly, Single Metal 0.6 µm Buried contacts w/silicided poly							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	60%	Tuse:	55 °C
Ea:	0.7	Vuse:	5.5 Volts
β:	1		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
24579	INFANT LIFE	125C, 7.0 VOLTS	88	48	HOUR	0
		TOTAL:	621	FAIL RATE (Fits): 1.48E+06		0
24576	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
24577	STORAGE LIFE	125C	203	24	HOUR	
	MOISTURE SOAK	30C/60% R.H.	203	144	HOUR	
	CONVECTION REFLOW	220C	195	3	PASS	0
		TOTAL:				0
24578	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS5002 JAN '00 MONITOR

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS5002	C4	9948	DM925589AAG	80	MQFP	550	Carsem
PROCESS Single Poly, Single Metal 0.6 μm Buried contacts w/silicided poly							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
25057	INFANT LIFE	125C, 7.0 VOLTS	77	48	HOUR	
TOTAL:			FAIL RATE (Fits):		DEVICE HRS: 1.29E+06	
25054	ULTRASOUND	J-STD-020	4			0
TOTAL:						0
25055	STORAGE LIFE	125C	203	24	HOUR	
	MOISTURE SOAK	30C/60% R.H.	203	144	HOUR	
	VAPOR PHASE REFLOW	220C	201	3	PASS	0
TOTAL:						0
25056	PRECONDITION U/S	J-STD-020	4			0
TOTAL:						0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS80C320 OCT '99 MONITOR

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS80C320	C5	9938	DH925592AAB	40	DIP	600	CPS (ChipPac, C
PROCESS Single Poly, Single Metal 0.6 μm Poly 1 Silicide							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
24584	INFANT LIFE	125C, 7.0 VOLTS	234	48	HOUR	0
24585	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	76	336	HOUR	0
		125C, 7.0 VOLTS	76	1000	HOUR	0
		TOTAL:	30	DEVICE HRS: 3.05E+07		0
24586	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
		TOTAL:				0
24587	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			77	959	HOUR	0
		TOTAL:				0
24588	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED	37	96	HOUR	1
		TOTAL:				1
JOB NO	FAILURE MODE	FAILURE MECHANISM	CORRECTIVE ACTION			
24588	CONTINUITY	NOT ANALYZED	NA			

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS87520 AUG '99 MONITOR,D.P.-ANAM,K

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS87C520	A11	9922	DN850735AAB	44	LCC	650	ASI (Anam, K)

JOB_NO	DESCRIPTION	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
24402	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
24403	STORAGE LIFE	125C	238	24	HOUR	
	MOISTURE SOAK	30C/60% R.H.	238	240	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	228	3	PASS	0
		TOTAL:				0
24404	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
24407	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
		-55C TO 125C	40	1000	CYCL	0
		TOTAL:				0
24408	HAST	130C, 85%R.H.,5.5V	55	100	HOUR	0
		TOTAL:				0
24409	STORAGE LIFE	150C	51	336	HOUR	0
		150C	51	1000	HOUR	0
		TOTAL:				0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS87C520 NOV '99 MONITOR

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS87C520	A14	9931	DN901118AAB	44	LCC	650	ASI (Anam, K)
PROCESS Double Poly, Single Metal 0.8 μm EPROM w/silicided poly(s)							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf: Tuse:
 Ea: Vuse:
 β:

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
24800	INFANT LIFE	125C, 7.0 VOLTS	219	48	HOUR	0
		125C, 7.0 VOLTS	219	48	HOUR	0
24801	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
		125C, 7.0 VOLTS	77	336	HOUR	0
TOTAL:			36	DEVICE HRS: 2.54E+07		0
24797	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
24798	STORAGE LIFE	125C	226	24	HOUR	
	MOISTURE SOAK	30C/60% R.H.	226	240	HOUR	
	VAPOR PHASE REFLOW	217C	223	3	PASS	3
TOTAL:						3
24799	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
24802	TEMP CYCLE	-55C TO 125C	40	300	CYCL	
		TOTAL:				
24803	HAST	130C, 85%R.H.,5.5V	56	100	HOUR	
		TOTAL:				
24804	STORAGE LIFE	150C	40	336	HOUR	0
		TOTAL:				0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS87C520 NOV '99 MONITOR

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS87C520	A14	9931	DN901118AAB	44	LCC	650	ASI (Anam, K)
PROCESS Double Poly, Single Metal 0.8 μm EPROM w/silicided poly(s)							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	60%	Tuse:	55 °C
Ea:	0.7	Vuse:	5.5 Volts
β:	1		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
JOB NO	FAILURE MODE	FAILURE MECHANISM	CORRECTIVE ACTION			
24798	OP40 (2)	IN VERIFICATION				NA
24798	EPROM	IN VERIFICATION				NA

Empty "No of Fails" TOTAL implies that Material is still in stress